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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Active
Number of LABs/CLBs	6036
Number of Logic Elements/Cells	-
Total RAM Bits	-
Number of I/O	171
Number of Gates	108000
Voltage - Supply	2.25V ~ 5.25V
Mounting Type	Surface Mount
Operating Temperature	-55°C ~ 125°C (TJ)
Package / Case	208-BFCQFP with Tie Bar
Supplier Device Package	208-CQFP (75x75)
Purchase URL	https://www.e-xfl.com/product-detail/microchip-technology/a54sx72a-1cq208b

Probing Capabilities

SX-A devices also provide an internal probing capability that is accessed with the JTAG pins. The Silicon Explorer II diagnostic hardware is used to control the TDI, TCK, TMS, and TDO pins to select the desired nets for debugging. The user assigns the selected internal nets in Actel Silicon Explorer II software to the PRA/PRB output pins for observation. Silicon Explorer II automatically places the device into JTAG mode. However, probing functionality is only activated when the TRST pin is driven high or left floating, allowing the internal pull-up resistor to pull TRST High. If the TRST pin is held Low, the TAP controller remains in the Test-Logic-Reset state so no probing can be performed. However, the user must drive the TRST pin High or allow the internal pull-up resistor to pull TRST High.

When selecting the **Reserve Probe Pin** box as shown in Figure 1-12 on page 1-9, direct the layout tool to reserve the PRA and PRB pins as dedicated outputs for probing. This **Reserve** option is merely a guideline. If the designer assigns user I/Os to the PRA and PRB pins and selects the **Reserve Probe Pin** option, Designer Layout will override the **Reserve Probe Pin** option and place the user I/Os on those pins.

To allow probing capabilities, the security fuse must not be programmed. Programming the security fuse disables the JTAG and probe circuitry. Table 1-9 summarizes the possible device configurations for probing once the device leaves the Test-Logic-Reset JTAG state.

Table 1-9 • Device Configuration Options for Probe Capability (TRST Pin Reserved)

JTAG Mode	TRST ¹	Security Fuse Programmed	PRA, PRB ²	TDI, TCK, TDO ²
Dedicated	Low	No	User I/O ³	JTAG Disabled
	High	No	Probe Circuit Outputs	JTAG I/O
Flexible	Low	No	User I/O ³	User I/O ³
	High	No	Probe Circuit Outputs	JTAG I/O
		Yes	Probe Circuit Secured	Probe Circuit Secured

Notes:

1. If the TRST pin is not reserved, the device behaves according to TRST = High as described in the table.
2. Avoid using the TDI, TCK, TDO, PRA, and PRB pins as input or bidirectional ports. Since these pins are active during probing, input signals will not pass through these pins and may cause contention.
3. If no user signal is assigned to these pins, they will behave as unused I/Os in this mode. Unused pins are automatically tristated by the Designer software.

Related Documents

Application Notes

Global Clock Networks in Actel's Antifuse Devices

http://www.actel.com/documents/GlobalClk_AN.pdf

Using A54SX72A and RT54SX72S Quadrant Clocks

http://www.actel.com/documents/QCLK_AN.pdf

Implementation of Security in Actel Antifuse FPGAs

http://www.actel.com/documents/Antifuse_Security_AN.pdf

Actel eX, SX-A, and RTSX-S I/Os

http://www.actel.com/documents/AntifuseIO_AN.pdf

Actel SX-A and RT54SX-S Devices in Hot-Swap and Cold-Sparing Applications

http://www.actel.com/documents/HotSwapColdSparing_AN.pdf

Programming Antifuse Devices

http://www.actel.com/documents/AntifuseProgram_AN.pdf

Datasheets

HiRel SX-A Family FPGAs

http://www.actel.com/documents/HR SXA_DS.pdf

SX-A Automotive Family FPGAs

http://www.actel.com/documents/SXA_Auto_DS.pdf

User's Guides

Silicon Sculptor User's Guide

http://www.actel.com/documents/SiliSculptII_Sculpt3_ug.pdf

Pin Description

CLKA/B, I/O **Clock A and B**

These pins are clock inputs for clock distribution networks. Input levels are compatible with standard TTL, LVTTTL, LVCMOS2, 3.3 V PCI, or 5 V PCI specifications. The clock input is buffered prior to clocking the R-cells. When not used, this pin must be tied Low or High (NOT left floating) on the board to avoid unwanted power consumption.

For A54SX72A, these pins can also be configured as user I/Os. When employed as user I/Os, these pins offer built-in programmable pull-up or pull-down resistors active during power-up only. When not used, these pins must be tied Low or High (NOT left floating).

QCLKA/B/C/D, I/O **Quadrant Clock A, B, C, and D**

These four pins are the quadrant clock inputs and are only used for A54SX72A with A, B, C, and D corresponding to bottom-left, bottom-right, top-left, and top-right quadrants, respectively. They are clock inputs for clock distribution networks. Input levels are compatible with standard TTL, LVTTTL, LVCMOS2, 3.3 V PCI, or 5 V PCI specifications. Each of these clock inputs can drive up to a quarter of the chip, or they can be grouped together to drive multiple quadrants. The clock input is buffered prior to clocking the R-cells. When not used, these pins must be tied Low or High on the board (NOT left floating).

These pins can also be configured as user I/Os. When employed as user I/Os, these pins offer built-in programmable pull-up or pull-down resistors active during power-up only.

GND **Ground**

Low supply voltage.

HCLK **Dedicated (Hardwired) Array Clock**

This pin is the clock input for sequential modules. Input levels are compatible with standard TTL, LVTTTL, LVCMOS2, 3.3 V PCI, or 5 V PCI specifications. This input is directly wired to each R-cell and offers clock speeds independent of the number of R-cells being driven. When not used, HCLK must be tied Low or High on the board (NOT left floating). When used, this pin should be held Low or High during power-up to avoid unwanted static power consumption.

I/O **Input/Output**

The I/O pin functions as an input, output, tristate, or bidirectional buffer. Based on certain configurations, input and output levels are compatible with standard TTL, LVTTTL, LVCMOS2, 3.3 V PCI or 5 V PCI specifications. Unused I/O pins are automatically tristated by the Designer software.

NC **No Connection**

This pin is not connected to circuitry within the device and can be driven to any voltage or be left floating with no effect on the operation of the device.

PRA/B, I/O **Probe A/B**

The Probe pin is used to output data from any user-defined design node within the device. This independent diagnostic pin can be used in conjunction with the other probe pin to allow real-time diagnostic output of any signal path within the device. The Probe pin can be used as a user-defined I/O when verification has been completed. The pin's probe capabilities can be permanently disabled to protect programmed design confidentiality.

TCK, I/O **Test Clock**

Test clock input for diagnostic probe and device programming. In Flexible mode, TCK becomes active when the TMS pin is set Low (refer to Table 1-6 on page 1-9). This pin functions as an I/O when the boundary scan state machine reaches the "logic reset" state.

TDI, I/O **Test Data Input**

Serial input for boundary scan testing and diagnostic probe. In Flexible mode, TDI is active when the TMS pin is set Low (refer to Table 1-6 on page 1-9). This pin functions as an I/O when the boundary scan state machine reaches the "logic reset" state.

TDO, I/O **Test Data Output**

Serial output for boundary scan testing. In flexible mode, TDO is active when the TMS pin is set Low (refer to Table 1-6 on page 1-9). This pin functions as an I/O when the boundary scan state machine reaches the "logic reset" state. When Silicon Explorer II is being used, TDO will act as an output when the checksum command is run. It will return to user I/O when checksum is complete.

TMS **Test Mode Select**

The TMS pin controls the use of the IEEE 1149.1 Boundary Scan pins (TCK, TDI, TDO, TRST). In flexible mode when the TMS pin is set Low, the TCK, TDI, and TDO pins are boundary scan pins (refer to Table 1-6 on page 1-9). Once the boundary scan pins are in test mode, they will remain in that mode until the internal boundary scan state machine reaches the logic reset state. At this point, the boundary scan pins will be released and will function as regular I/O pins. The logic reset state is reached five TCK cycles after the TMS pin is set High. In dedicated test mode, TMS functions as specified in the IEEE 1149.1 specifications.

TRST, I/O **Boundary Scan Reset Pin**

Once it is configured as the JTAG Reset pin, the TRST pin functions as an active low input to asynchronously initialize or reset the boundary scan circuit. The TRST pin is equipped with an internal pull-up resistor. This pin functions as an I/O when the **Reserve JTAG Reset Pin** is not selected in Designer.

V_{CC} **Supply Voltage**

Supply voltage for I/Os. See Table 2-2 on page 2-1. All V_{CC} power pins in the device should be connected.

V_{CCA} **Supply Voltage**

Supply voltage for array. See Table 2-2 on page 2-1. All V_{CCA} power pins in the device should be connected.

Figure 2-1 shows the 5 V PCI V/I curve and the minimum and maximum PCI drive characteristics of the SX-A family.

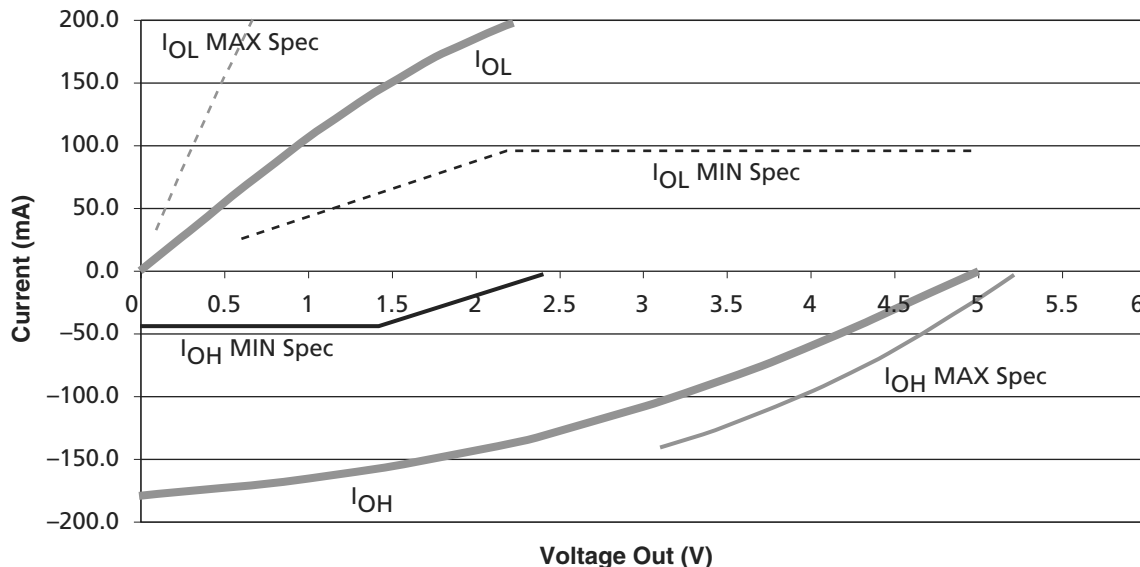


Figure 2-1 • 5 V PCI V/I Curve for SX-A Family

$$I_{OH} = 11.9 * (V_{OUT} - 5.25) * (V_{OUT} + 2.45)$$

for $V_{CCI} > V_{OUT} > 3.1V$

EQ 2-1

$$I_{OL} = 78.5 * V_{OUT} * (4.4 - V_{OUT})$$

for $0V < V_{OUT} < 0.71V$

EQ 2-2

Table 2-9 • DC Specifications (3.3 V PCI Operation)

Symbol	Parameter	Condition	Min.	Max.	Units
V_{CCA}	Supply Voltage for Array		2.25	2.75	V
V_{CCI}	Supply Voltage for I/Os		3.0	3.6	V
V_{IH}	Input High Voltage		$0.5V_{CCI}$	$V_{CCI} + 0.5$	V
V_{IL}	Input Low Voltage		-0.5	$0.3V_{CCI}$	V
I_{IPU}	Input Pull-up Voltage ¹		$0.7V_{CCI}$	–	V
I_{IL}	Input Leakage Current ²	$0 < V_{IN} < V_{CCI}$	-10	+10	μA
V_{OH}	Output High Voltage	$I_{OUT} = -500 \mu A$	$0.9V_{CCI}$	–	V
V_{OL}	Output Low Voltage	$I_{OUT} = 1,500 \mu A$		$0.1V_{CCI}$	V
C_{IN}	Input Pin Capacitance ³		–	10	pF
C_{CLK}	CLK Pin Capacitance		5	12	pF

Notes:

1. This specification should be guaranteed by design. It is the minimum voltage to which pull-up resistors are calculated to pull a floated network. Designers should ensure that the input buffer is conducting minimum current at this input voltage in applications sensitive to static power utilization.
2. Input leakage currents include hi-Z output leakage for all bidirectional buffers with tristate outputs.
3. Absolute maximum pin capacitance for a PCI input is 10 pF (except for CLK).

Figure 2-2 shows the 3.3 V PCI V/I curve and the minimum and maximum PCI drive characteristics of the SX-A family.

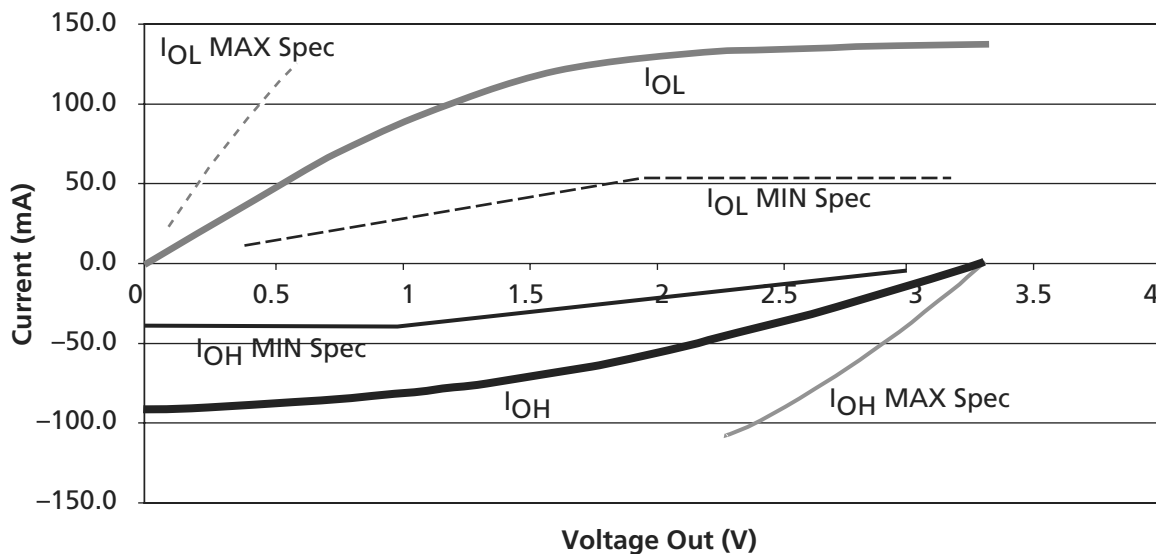


Figure 2-2 • 3.3 V PCI V/I Curve for SX-A Family

$$I_{OH} = (98.0/V_{CCI}) * (V_{OUT} - V_{CCI}) * (V_{OUT} + 0.4V_{CCI})$$

for $0.7 V_{CCI} < V_{OUT} < V_{CCI}$

EQ 2-3

$$I_{OL} = (256/V_{CCI}) * V_{OUT} * (V_{CCI} - V_{OUT})$$

for $0V < V_{OUT} < 0.18 V_{CCI}$

EQ 2-4

Power Dissipation

A critical element of system reliability is the ability of electronic devices to safely dissipate the heat generated during operation. The thermal characteristics of a circuit depend on the device and package used, the operating temperature, the operating current, and the system's ability to dissipate heat.

A complete power evaluation should be performed early in the design process to help identify potential heat-related problems in the system and to prevent the system from exceeding the device's maximum allowed junction temperature.

The actual power dissipated by most applications is significantly lower than the power the package can dissipate. However, a thermal analysis should be performed for all projects. To perform a power evaluation, follow these steps:

1. Estimate the power consumption of the application.
2. Calculate the maximum power allowed for the device and package.
3. Compare the estimated power and maximum power values.

Estimating Power Dissipation

The total power dissipation for the SX-A family is the sum of the DC power dissipation and the AC power dissipation:

$$P_{\text{Total}} = P_{\text{DC}} + P_{\text{AC}}$$

EQ 2-5

DC Power Dissipation

The power due to standby current is typically a small component of the overall power. An estimation of DC power dissipation under typical conditions is given by:

$$P_{\text{DC}} = I_{\text{standby}} * V_{\text{CCA}}$$

EQ 2-6

Note: For other combinations of temperature and voltage settings, refer to the *eX, SX-A and RT54SX-S Power Calculator*.

AC Power Dissipation

The power dissipation of the SX-A family is usually dominated by the dynamic power dissipation. Dynamic power dissipation is a function of frequency, equivalent capacitance, and power supply voltage. The AC power dissipation is defined as follows:

$$P_{\text{AC}} = P_{\text{C-cells}} + P_{\text{R-cells}} + P_{\text{CLKA}} + P_{\text{CLKB}} + P_{\text{HCLK}} + P_{\text{Output Buffer}} + P_{\text{Input Buffer}}$$

EQ 2-7

or:

$$P_{\text{AC}} = V_{\text{CCA}}^2 * [(m * C_{\text{EQCM}} * f_m)_{\text{C-cells}} + (m * C_{\text{EQSM}} * f_m)_{\text{R-cells}} + (n * C_{\text{EQI}} * f_n)_{\text{Input Buffer}} + (p * (C_{\text{EQO}} + C_L) * f_p)_{\text{Output Buffer}} + (0.5 * (q_1 * C_{\text{EQCR}} * f_{q1}) + (r_1 * f_{q1}))_{\text{CLKA}} + (0.5 * (q_2 * C_{\text{EQCR}} * f_{q2}) + (r_2 * f_{q2}))_{\text{CLKB}} + (0.5 * (s_1 * C_{\text{EQHV}} * f_{s1}) + (C_{\text{EQHF}} * f_{s1}))_{\text{HCLK}}]$$

EQ 2-8

Theta-JA

Junction-to-ambient thermal resistance (θ_{JA}) is determined under standard conditions specified by JESD-51 series but has little relevance in actual performance of the product in real application. It should be employed with caution but is useful for comparing the thermal performance of one package to another.

A sample calculation to estimate the absolute maximum power dissipation allowed (worst case) for a 329-pin PBGA package at still air is as follows. i.e.:

$$\theta_{JA} = 17.1^{\circ}\text{C/W} \text{ is taken from Table 2-12 on page 2-11}$$

$$T_A = 125^{\circ}\text{C} \text{ is the maximum limit of ambient (from the datasheet)}$$

$$\text{Max. Allowed Power} = \frac{\text{Max Junction Temp} - \text{Max. Ambient Temp}}{\theta_{JA}} = \frac{150^{\circ}\text{C} - 125^{\circ}\text{C}}{17.1^{\circ}\text{C/W}} = 1.46 \text{ W}$$

EQ 2-11

The device's power consumption must be lower than the calculated maximum power dissipation by the package.

The power consumption of a device can be calculated using the Actel power calculator. If the power consumption is higher than the device's maximum allowable power dissipation, then a heat sink can be attached on top of the case or the airflow inside the system must be increased.

Theta-JC

Junction-to-case thermal resistance (θ_{JC}) measures the ability of a device to dissipate heat from the surface of the chip to the top or bottom surface of the package. It is applicable for packages used with external heat sinks and only applies to situations where all or nearly all of the heat is dissipated through the surface in consideration. If the power consumption is higher than the calculated maximum power dissipation of the package, then a heat sink is required.

Calculation for Heat Sink

For example, in a design implemented in a FG484 package, the power consumption value using the power calculator is 3.00 W. The user-dependent data T_J and T_A are given as follows:

$$T_J = 110^{\circ}\text{C}$$

$$T_A = 70^{\circ}\text{C}$$

From the datasheet:

$$\theta_{JA} = 18.0^{\circ}\text{C/W}$$

$$\theta_{JC} = 3.2^{\circ}\text{C/W}$$

$$P = \frac{\text{Max Junction Temp} - \text{Max. Ambient Temp}}{\theta_{JA}} = \frac{110^{\circ}\text{C} - 70^{\circ}\text{C}}{18.0^{\circ}\text{C/W}} = 2.22 \text{ W}$$

EQ 2-12

The 2.22 W power is less than then required 3.00 W; therefore, the design requires a heat sink or the airflow where the device is mounted should be increased. The design's junction-to-air thermal resistance requirement can be estimated by:

$$\theta_{JA} = \frac{\text{Max Junction Temp} - \text{Max. Ambient Temp}}{P} = \frac{110^{\circ}\text{C} - 70^{\circ}\text{C}}{3.00 \text{ W}} = 13.33^{\circ}\text{C/W}$$

EQ 2-13

Output Buffer Delays

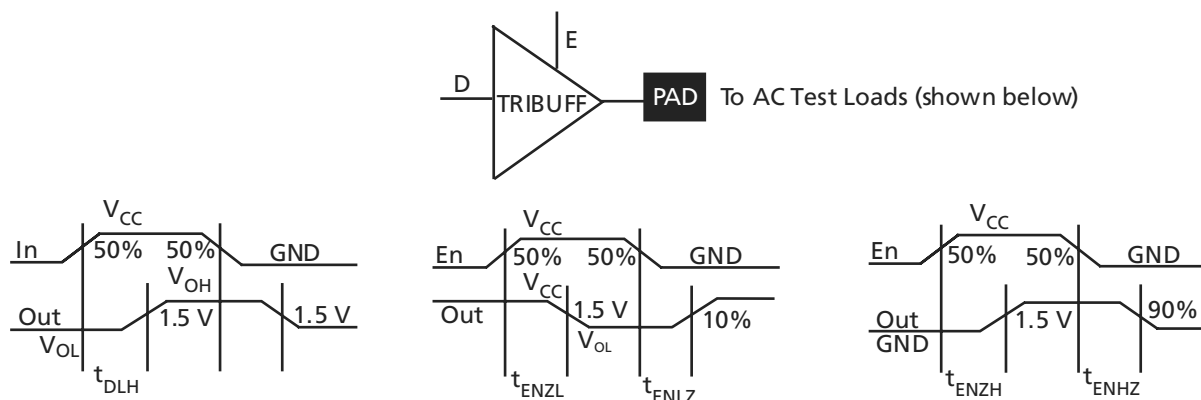


Figure 2-4 • Output Buffer Delays

AC Test Loads

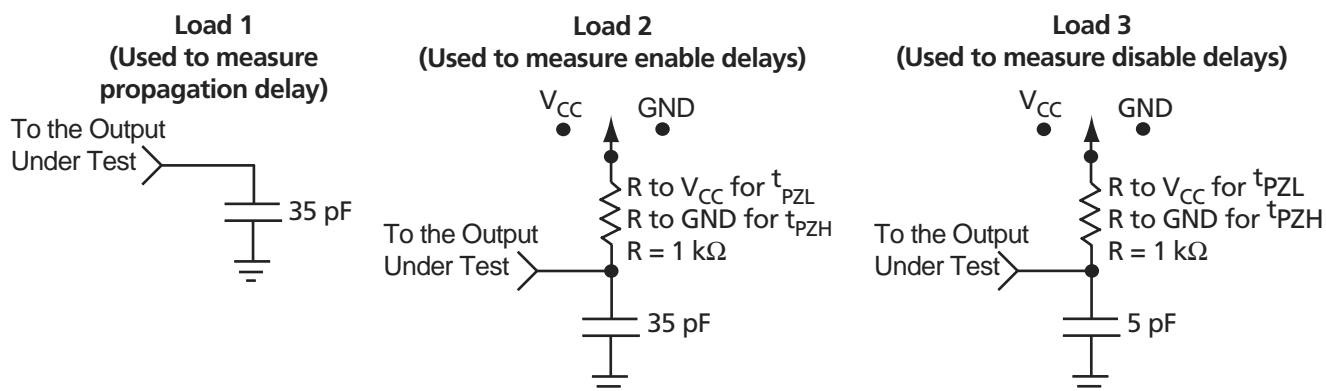


Figure 2-5 • AC Test Loads

Table 2-14 • A54SX08A Timing Characteristics (Continued)

(Worst-Case Commercial Conditions, $V_{CCA} = 2.25\text{ V}$, $V_{CCI} = 3.0\text{ V}$, $T_J = 70^\circ\text{C}$)

Parameter	Description	-2 Speed		-1 Speed		Std. Speed		-F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t_{INYH}	Input Data Pad to Y High 5 V PCI		0.5		0.6		0.7		0.9	ns
t_{INYL}	Input Data Pad to Y Low 5 V PCI		0.8		0.9		1.1		1.5	ns
t_{INYH}	Input Data Pad to Y High 5 V TTL		0.5		0.6		0.7		0.9	ns
t_{INYL}	Input Data Pad to Y Low 5 V TTL		0.8		0.9		1.1		1.5	ns
Input Module Predicted Routing Delays²										
t_{IRD1}	FO = 1 Routing Delay		0.3		0.3		0.4		0.6	ns
t_{IRD2}	FO = 2 Routing Delay		0.5		0.5		0.6		0.8	ns
t_{IRD3}	FO = 3 Routing Delay		0.6		0.7		0.8		1.1	ns
t_{IRD4}	FO = 4 Routing Delay		0.8		0.9		1		1.4	ns
t_{IRD8}	FO = 8 Routing Delay		1.4		1.5		1.8		2.5	ns
t_{IRD12}	FO = 12 Routing Delay		2		2.2		2.6		3.6	ns

Notes:

- For dual-module macros, use $t_{PD} + t_{RD1} + t_{PDn}$, $t_{RCO} + t_{RD1} + t_{PDn}$, or $t_{PD1} + t_{RD1} + t_{SUD}$, whichever is appropriate.
- Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.

Table 2-22 • **A54SX16A Timing Characteristics**
(Worst-Case Commercial Conditions $V_{CCA} = 2.25\text{ V}$, $V_{CCI} = 2.25\text{ V}$, $T_J = 70^\circ\text{C}$)

Parameter	Description	–3 Speed*		–2 Speed		–1 Speed		Std. Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Dedicated (Hardwired) Array Clock Networks												
t _{HCKH}	Input Low to High (Pad to R-cell Input)		1.2		1.4		1.6		1.8		2.8	ns
t _{HCKL}	Input High to Low (Pad to R-cell Input)		1.0		1.1		1.2		1.5		2.2	ns
t _{HPWH}	Minimum Pulse Width High	1.4		1.7		1.9		2.2		3.0		ns
t _{HPWL}	Minimum Pulse Width Low	1.4		1.7		1.9		2.2		3.0		ns
t _{HCKSW}	Maximum Skew		0.3		0.3		0.4		0.4		0.7	ns
t _{HP}	Minimum Period	2.8		3.4		3.8		4.4		6.0		ns
f _{HMAX}	Maximum Frequency		357		294		263		227		167	MHz
Routed Array Clock Networks												
t _{RCKH}	Input Low to High (Light Load) (Pad to R-cell Input)		1.0		1.2		1.3		1.6		2.2	ns
t _{RCKL}	Input High to Low (Light Load) (Pad to R-cell Input)		1.1		1.3		1.5		1.7		2.4	ns
t _{RCKH}	Input Low to High (50% Load) (Pad to R-cell Input)		1.1		1.3		1.5		1.7		2.4	ns
t _{RCKL}	Input High to Low (50% Load) (Pad to R-cell Input)		1.1		1.3		1.5		1.7		2.4	ns
t _{RCKH}	Input Low to High (100% Load) (Pad to R-cell Input)		1.3		1.5		1.7		2.0		2.8	ns
t _{RCKL}	Input High to Low (100% Load) (Pad to R-cell Input)		1.3		1.5		1.7		2.0		2.8	ns
t _{RPWH}	Minimum Pulse Width High	1.4		1.7		1.9		2.2		3.0		ns
t _{RPWL}	Minimum Pulse Width Low	1.4		1.7		1.9		2.2		3.0		ns
t _{RCKSW}	Maximum Skew (Light Load)		0.8		0.9		1.0		1.2		1.7	ns
t _{RCKSW}	Maximum Skew (50% Load)		0.8		0.9		1.0		1.2		1.7	ns
t _{RCKSW}	Maximum Skew (100% Load)		1.0		1.1		1.3		1.5		2.1	ns

Note: *All –3 speed grades have been discontinued.

Table 2-31 • **A54SX32A Timing Characteristics**
(Worst-Case Commercial Conditions $V_{CCA} = 2.25\text{ V}$, $V_{CCI} = 4.75\text{ V}$, $T_J = 70^\circ\text{C}$)

Parameter	Description	–3 Speed*		–2 Speed		–1 Speed		Std. Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Dedicated (Hardwired) Array Clock Networks												
t _{HCKH}	Input Low to High (Pad to R-cell Input)		1.7		1.9		2.2		2.6		4.0	ns
t _{HCKL}	Input High to Low (Pad to R-cell Input)		1.7		2.0		2.2		2.6		4.0	ns
t _{HPWH}	Minimum Pulse Width High	1.4		1.6		1.8		2.1		2.9		ns
t _{HPWL}	Minimum Pulse Width Low	1.4		1.6		1.8		2.1		2.9		ns
t _{HCKSW}	Maximum Skew		0.6		0.6		0.7		0.8		1.3	ns
t _{HP}	Minimum Period	2.8		3.2		3.6		4.2		5.8		ns
f _{HMAX}	Maximum Frequency		357		313		278		238		172	MHz
Routed Array Clock Networks												
t _{RCKH}	Input Low to High (Light Load) (Pad to R-cell Input)		2.2		2.5		2.8		3.3		4.7	ns
t _{RCKL}	Input High to Low (Light Load) (Pad to R-cell Input)		2.1		2.5		2.8		3.3		4.5	ns
t _{RCKH}	Input Low to High (50% Load) (Pad to R-cell Input)		2.4		2.7		3.1		3.6		5.1	ns
t _{RCKL}	Input High to Low (50% Load) (Pad to R-cell Input)		2.2		2.6		2.9		3.4		4.7	ns
t _{RCKH}	Input Low to High (100% Load) (Pad to R-cell Input)		2.5		2.8		3.2		3.8		5.3	ns
t _{RCKL}	Input High to Low (100% Load) (Pad to R-cell Input)		2.4		2.8		3.1		3.7		5.2	ns
t _{RPWH}	Minimum Pulse Width High	1.4		1.6		1.8		2.1		2.9		ns
t _{RPWL}	Minimum Pulse Width Low	1.4		1.6		1.8		2.1		2.9		ns
t _{RCKSW}	Maximum Skew (Light Load)		1.0		1.1		1.3		1.5		2.1	ns
t _{RCKSW}	Maximum Skew (50% Load)		1.0		1.1		1.3		1.5		2.1	ns
t _{RCKSW}	Maximum Skew (100% Load)		1.0		1.1		1.3		1.5		2.1	ns

Note: *All –3 speed grades have been discontinued.

Table 2-32 • A54SX32A Timing Characteristics

(Worst-Case Commercial Conditions $V_{CCA} = 2.25\text{ V}$, $V_{CCI} = 2.3\text{ V}$, $T_J = 70^\circ\text{C}$)

Parameter	Description	–3 Speed ¹		–2 Speed		–1 Speed		Std. Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
2.5 V LVCMOS Output Module Timing ^{2,3}												
t _{DLH}	Data-to-Pad Low to High	3.3		3.8		4.2		5.0		7.0		ns
t _{DHL}	Data-to-Pad High to Low	2.5		2.9		3.2		3.8		5.3		ns
t _{DHLS}	Data-to-Pad High to Low—low slew	11.1		12.8		14.5		17.0		23.8		ns
t _{ENZL}	Enable-to-Pad, Z to L	2.4		2.8		3.2		3.7		5.2		ns
t _{ENZLS}	Data-to-Pad, Z to L—low slew	11.8		13.7		15.5		18.2		25.5		ns
t _{ENZH}	Enable-to-Pad, Z to H	3.3		3.8		4.2		5.0		7.0		ns
t _{ENLZ}	Enable-to-Pad, L to Z	2.1		2.5		2.8		3.3		4.7		ns
t _{ENHZ}	Enable-to-Pad, H to Z	2.5		2.9		3.2		3.8		5.3		ns
d _{TLH} ⁴	Delta Low to High	0.031		0.037		0.043		0.051		0.071		ns/pF
d _{THL} ⁴	Delta High to Low	0.017		0.017		0.023		0.023		0.037		ns/pF
d _{THLS} ⁴	Delta High to Low—low slew	0.057		0.06		0.071		0.086		0.117		ns/pF

Note:

1. All –3 speed grades have been discontinued.
2. Delays based on 35 pF loading.
3. The equivalent IO Attribute settings for 2.5 V LVCMOS is 2.5 V LVTTTL in the software.
4. To obtain the slew rate, substitute the appropriate Delta value, load capacitance, and the V_{CCI} value into the following equation:

$$\text{Slew Rate [V/ns]} = (0.1 * V_{CCI} - 0.9 * V_{CCI}) / (C_{load} * d_{T[LH|HL|HLS]})$$
where C_{load} is the load capacitance driven by the I/O in pF
 $d_{T[LH|HL|HLS]}$ is the worst case delta value from the datasheet in ns/pF.

Table 2-34 • A54SX32A Timing Characteristics
(Worst-Case Commercial Conditions $V_{CCA} = 2.25\text{ V}$, $V_{CCI} = 4.75\text{ V}$, $T_J = 70^\circ\text{C}$)

Parameter	Description	–3 Speed ¹		–2 Speed		–1 Speed		Std. Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
5 V PCI Output Module Timing ²												
t _{DLH}	Data-to-Pad Low to High	2.1		2.4		2.8		3.2		4.5		ns
t _{DHL}	Data-to-Pad High to Low	2.8		3.2		3.6		4.2		5.9		ns
t _{ENZL}	Enable-to-Pad, Z to L	1.3		1.5		1.7		2.0		2.8		ns
t _{ENZH}	Enable-to-Pad, Z to H	2.1		2.4		2.8		3.2		4.5		ns
t _{ENLZ}	Enable-to-Pad, L to Z	3.0		3.5		3.9		4.6		6.4		ns
t _{ENHZ}	Enable-to-Pad, H to Z	2.8		3.2		3.6		4.2		5.9		ns
d _{TLH} ³	Delta Low to High	0.016		0.016		0.02		0.022		0.032		ns/pF
d _{THL} ³	Delta High to Low	0.026		0.03		0.032		0.04		0.052		ns/pF
5 V TTL Output Module Timing ⁴												
t _{DLH}	Data-to-Pad Low to High	1.9		2.2		2.5		2.9		4.1		ns
t _{DHL}	Data-to-Pad High to Low	2.5		2.9		3.3		3.9		5.4		ns
t _{DHLS}	Data-to-Pad High to Low—low slew	6.6		7.6		8.6		10.1		14.2		ns
t _{ENZL}	Enable-to-Pad, Z to L	2.1		2.4		2.7		3.2		4.5		ns
t _{ENZLS}	Enable-to-Pad, Z to L—low slew	7.4		8.4		9.5		11.0		15.4		ns
t _{ENZH}	Enable-to-Pad, Z to H	1.9		2.2		2.5		2.9		4.1		ns
t _{ENLZ}	Enable-to-Pad, L to Z	3.6		4.2		4.7		5.6		7.8		ns
t _{ENHZ}	Enable-to-Pad, H to Z	2.5		2.9		3.3		3.9		5.4		ns
d _{TLH} ³	Delta Low to High	0.014		0.017		0.017		0.023		0.031		ns/pF
d _{THL} ³	Delta High to Low	0.023		0.029		0.031		0.037		0.051		ns/pF
d _{THLS} ³	Delta High to Low—low slew	0.043		0.046		0.057		0.066		0.089		ns/pF

Notes:

1. All –3 speed grades have been discontinued.
2. Delays based on 50 pF loading.
3. To obtain the slew rate, substitute the appropriate Delta value, load capacitance, and the V_{CCI} value into the following equation:

$$\text{Slew Rate [V/ns]} = (0.1 * V_{CCI} - 0.9 * V_{CCI}) / (C_{load} * d_{T[HL|HL|HLS]})$$
 where C_{load} is the load capacitance driven by the I/O in pF
 $d_{T[HL|HL|HLS]}$ is the worst case delta value from the datasheet in ns/pF.
4. Delays based on 35 pF loading.

Table 2-36 • A54SX72A Timing Characteristics (Continued)
(Worst-Case Commercial Conditions $V_{CCA} = 2.25\text{ V}$, $V_{CCI} = 2.25\text{ V}$, $T_J = 70^\circ\text{C}$)

Parameter	Description	-3 Speed*		-2 Speed		-1 Speed		Std. Speed		-F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t_{QCKH}	Input Low to High (100% Load) (Pad to R-cell Input)		3.0		3.4		3.9		4.6		6.4	ns
t_{QCHKL}	Input High to Low (100% Load) (Pad to R-cell Input)		2.9		3.4		3.8		4.5		6.3	ns
t_{QPWH}	Minimum Pulse Width High	1.5		1.7		2.0		2.3		3.2		ns
t_{QPWL}	Minimum Pulse Width Low	1.5		1.7		2.0		2.3		3.2		ns
t_{QCKSW}	Maximum Skew (Light Load)		0.2		0.3		0.3		0.3		0.5	ns
t_{QCKSW}	Maximum Skew (50% Load)		0.4		0.5		0.5		0.6		0.9	ns
t_{QCKSW}	Maximum Skew (100% Load)		0.4		0.5		0.5		0.6		0.9	ns

Note: *All -3 speed grades have been discontinued.

Table 2-38 • **A54SX72A Timing Characteristics**
(Worst-Case Commercial Conditions $V_{CCA} = 2.25\text{ V}$, $V_{CCI} = 4.75\text{ V}$, $T_J = 70^\circ\text{C}$)

Parameter	Description	–3 Speed*		–2 Speed		–1 Speed		Std. Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Dedicated (Hardwired) Array Clock Networks												
t _{HCKH}	Input Low to High (Pad to R-cell Input)		1.6		1.8		2.1		2.4		3.8	ns
t _{HCKL}	Input High to Low (Pad to R-cell Input)		1.6		1.9		2.1		2.5		3.8	ns
t _{HPWH}	Minimum Pulse Width High	1.5		1.7		2.0		2.3		3.2		ns
t _{HPWL}	Minimum Pulse Width Low	1.5		1.7		2.0		2.3		3.2		ns
t _{HCKSW}	Maximum Skew		1.4		1.6		1.8		2.1		3.3	ns
t _{HP}	Minimum Period	3.0		3.4		4.0		4.6		6.4		ns
f _{HMAX}	Maximum Frequency		333		294		250		217		156	MHz
Routed Array Clock Networks												
t _{RCKH}	Input Low to High (Light Load) (Pad to R-cell Input)		2.3		2.6		3.0		3.5		4.9	ns
t _{RCKL}	Input High to Low (Light Load) (Pad to R-cell Input)		2.8		3.2		3.6		4.3		6.0	ns
t _{RCKH}	Input Low to High (50% Load) (Pad to R-cell Input)		2.5		2.9		3.2		3.8		5.3	ns
t _{RCKL}	Input High to Low (50% Load) (Pad to R-cell Input)		3.0		3.4		3.9		4.6		6.4	ns
t _{RCKH}	Input Low to High (100% Load) (Pad to R-cell Input)		2.6		3.0		3.4		3.9		5.5	ns
t _{RCKL}	Input High to Low (100% Load) (Pad to R-cell Input)		3.2		3.6		4.1		4.8		6.8	ns
t _{RPWH}	Minimum Pulse Width High	1.5		1.7		2.0		2.3		3.2		ns
t _{RPWL}	Minimum Pulse Width Low	1.5		1.7		2.0		2.3		3.2		ns
t _{RCKSW}	Maximum Skew (Light Load)		1.9		2.2		2.5		3.0		4.1	ns
t _{RCKSW}	Maximum Skew (50% Load)		1.9		2.2		2.5		3.0		4.1	ns
t _{RCKSW}	Maximum Skew (100% Load)		1.9		2.2		2.5		3.0		4.1	ns
Quadrant Array Clock Networks												
t _{QCKH}	Input Low to High (Light Load) (Pad to R-cell Input)		1.2		1.4		1.6		1.8		2.6	ns
t _{QCHKL}	Input High to Low (Light Load) (Pad to R-cell Input)		1.3		1.4		1.6		1.9		2.7	ns
t _{QCKH}	Input Low to High (50% Load) (Pad to R-cell Input)		1.4		1.6		1.8		2.1		3.0	ns
t _{QCHKL}	Input High to Low (50% Load) (Pad to R-cell Input)		1.4		1.7		1.9		2.2		3.1	ns

Note: *All –3 speed grades have been discontinued.

Table 2-39 • **A54SX72A Timing Characteristics**
(Worst-Case Commercial Conditions $V_{CCA} = 2.25\text{ V}$, $V_{CCI} = 2.3\text{ V}$, $T_J = 70^\circ\text{C}$)

Parameter	Description	–3 Speed ¹		–2 Speed		–1 Speed		Std. Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
2.5 V LVCMOS Output Module Timing ^{2, 3}												
t _{DLH}	Data-to-Pad Low to High	3.9		4.5		5.1		6.0		8.4		ns
t _{DHL}	Data-to-Pad High to Low	3.1		3.6		4.1		4.8		6.7		ns
t _{DHLS}	Data-to-Pad High to Low—low slew	12.7		14.6		16.5		19.4		27.2		ns
t _{ENZL}	Enable-to-Pad, Z to L	2.4		2.8		3.2		3.7		5.2		ns
t _{ENZLS}	Data-to-Pad, Z to L—low slew	11.8		13.7		15.5		18.2		25.5		ns
t _{ENZH}	Enable-to-Pad, Z to H	3.9		4.5		5.1		6.0		8.4		ns
t _{ENLZ}	Enable-to-Pad, L to Z	2.1		2.5		2.8		3.3		4.7		ns
t _{ENHZ}	Enable-to-Pad, H to Z	3.1		3.6		4.1		4.8		6.7		ns
d _{TLH} ⁴	Delta Low to High	0.031		0.037		0.043		0.051		0.071		ns/pF
d _{THL} ⁴	Delta High to Low	0.017		0.017		0.023		0.023		0.037		ns/pF
d _{THLS} ⁴	Delta High to Low—low slew	0.057		0.06		0.071		0.086		0.117		ns/pF

Note:

1. All –3 speed grades have been discontinued.
2. Delays based on 35 pF loading.
3. The equivalent IO Attribute settings for 2.5 V LVC MOS is 2.5 V LV TTL in the software.
4. To obtain the slew rate, substitute the appropriate Delta value, load capacitance, and the V_{CCI} value into the following equation:

$$\text{Slew Rate [V/ns]} = (0.1 * V_{CCI} - 0.9 * V_{CCI}) / (C_{load} * d_{T[LH|HL|HLS]})$$
 where C_{load} is the load capacitance driven by the I/O in pF
 $d_{T[LH|HL|HLS]}$ is the worst case delta value from the datasheet in ns/pF.

144-Pin TQFP			
Pin Number	A54SX08A Function	A54SX16A Function	A54SX32A Function
1	GND	GND	GND
2	TDI, I/O	TDI, I/O	TDI, I/O
3	I/O	I/O	I/O
4	I/O	I/O	I/O
5	I/O	I/O	I/O
6	I/O	I/O	I/O
7	I/O	I/O	I/O
8	I/O	I/O	I/O
9	TMS	TMS	TMS
10	V _{CCI}	V _{CCI}	V _{CCI}
11	GND	GND	GND
12	I/O	I/O	I/O
13	I/O	I/O	I/O
14	I/O	I/O	I/O
15	I/O	I/O	I/O
16	I/O	I/O	I/O
17	I/O	I/O	I/O
18	I/O	I/O	I/O
19	NC	NC	NC
20	V _{CCA}	V _{CCA}	V _{CCA}
21	I/O	I/O	I/O
22	TRST, I/O	TRST, I/O	TRST, I/O
23	I/O	I/O	I/O
24	I/O	I/O	I/O
25	I/O	I/O	I/O
26	I/O	I/O	I/O
27	I/O	I/O	I/O
28	GND	GND	GND
29	V _{CCI}	V _{CCI}	V _{CCI}
30	V _{CCA}	V _{CCA}	V _{CCA}
31	I/O	I/O	I/O
32	I/O	I/O	I/O
33	I/O	I/O	I/O
34	I/O	I/O	I/O
35	I/O	I/O	I/O
36	GND	GND	GND
37	I/O	I/O	I/O

144-Pin TQFP			
Pin Number	A54SX08A Function	A54SX16A Function	A54SX32A Function
38	I/O	I/O	I/O
39	I/O	I/O	I/O
40	I/O	I/O	I/O
41	I/O	I/O	I/O
42	I/O	I/O	I/O
43	I/O	I/O	I/O
44	V _{CCI}	V _{CCI}	V _{CCI}
45	I/O	I/O	I/O
46	I/O	I/O	I/O
47	I/O	I/O	I/O
48	I/O	I/O	I/O
49	I/O	I/O	I/O
50	I/O	I/O	I/O
51	I/O	I/O	I/O
52	I/O	I/O	I/O
53	I/O	I/O	I/O
54	PRB, I/O	PRB, I/O	PRB, I/O
55	I/O	I/O	I/O
56	V _{CCA}	V _{CCA}	V _{CCA}
57	GND	GND	GND
58	NC	NC	NC
59	I/O	I/O	I/O
60	HCLK	HCLK	HCLK
61	I/O	I/O	I/O
62	I/O	I/O	I/O
63	I/O	I/O	I/O
64	I/O	I/O	I/O
65	I/O	I/O	I/O
66	I/O	I/O	I/O
67	I/O	I/O	I/O
68	V _{CCI}	V _{CCI}	V _{CCI}
69	I/O	I/O	I/O
70	I/O	I/O	I/O
71	TDO, I/O	TDO, I/O	TDO, I/O
72	I/O	I/O	I/O
73	GND	GND	GND
74	I/O	I/O	I/O

176-Pin TQFP

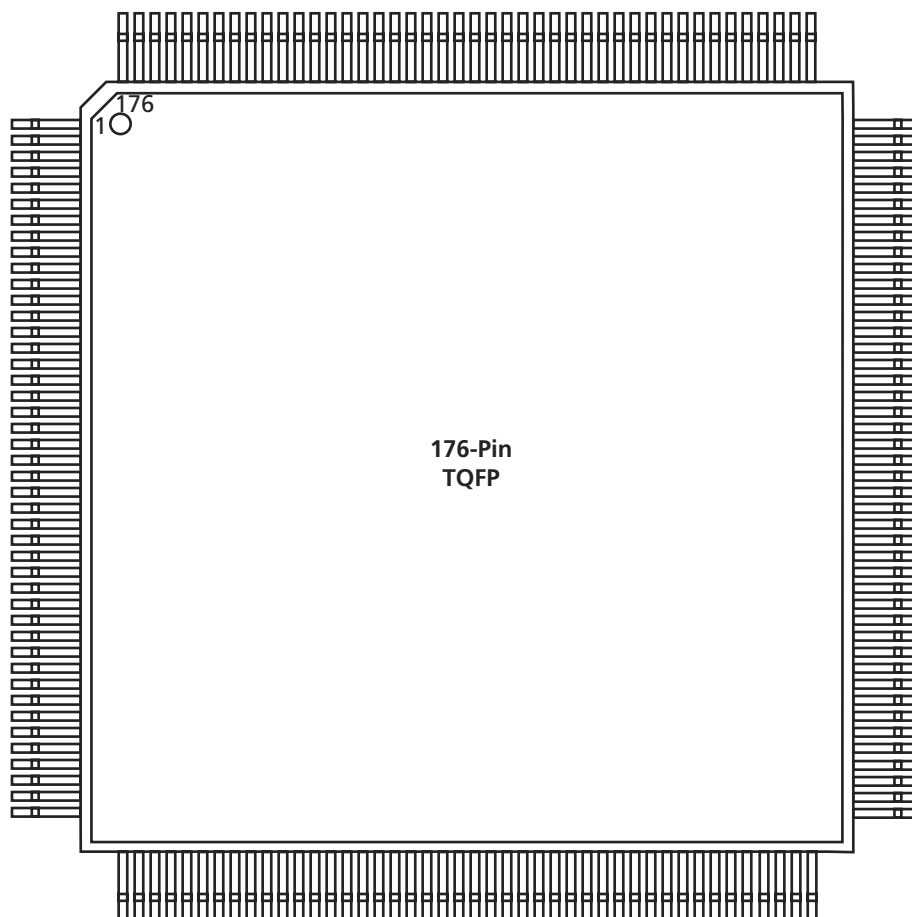


Figure 3-4 • 176-Pin TQFP (Top View)

Note

For Package Manufacturing and Environmental information, visit Resource center at <http://www.actel.com/products/rescenter/package/index.html>.

256-Pin FBGA			
Pin Number	A54SX16A Function	A54SX32A Function	A54SX72A Function
K5	I/O	I/O	I/O
K6	V _{CCI}	V _{CCI}	V _{CCI}
K7	GND	GND	GND
K8	GND	GND	GND
K9	GND	GND	GND
K10	GND	GND	GND
K11	V _{CCI}	V _{CCI}	V _{CCI}
K12	I/O	I/O	I/O
K13	I/O	I/O	I/O
K14	I/O	I/O	I/O
K15	NC	I/O	I/O
K16	I/O	I/O	I/O
L1	I/O	I/O	I/O
L2	I/O	I/O	I/O
L3	I/O	I/O	I/O
L4	I/O	I/O	I/O
L5	I/O	I/O	I/O
L6	I/O	I/O	I/O
L7	V _{CCI}	V _{CCI}	V _{CCI}
L8	V _{CCI}	V _{CCI}	V _{CCI}
L9	V _{CCI}	V _{CCI}	V _{CCI}
L10	V _{CCI}	V _{CCI}	V _{CCI}
L11	I/O	I/O	I/O
L12	I/O	I/O	I/O
L13	I/O	I/O	I/O
L14	I/O	I/O	I/O
L15	I/O	I/O	I/O
L16	NC	I/O	I/O
M1	I/O	I/O	I/O
M2	I/O	I/O	I/O
M3	I/O	I/O	I/O
M4	I/O	I/O	I/O
M5	I/O	I/O	I/O
M6	I/O	I/O	I/O
M7	I/O	I/O	QCLKA
M8	PRB, I/O	PRB, I/O	PRB, I/O
M9	I/O	I/O	I/O

256-Pin FBGA			
Pin Number	A54SX16A Function	A54SX32A Function	A54SX72A Function
M10	I/O	I/O	I/O
M11	I/O	I/O	I/O
M12	NC	I/O	I/O
M13	I/O	I/O	I/O
M14	NC	I/O	I/O
M15	I/O	I/O	I/O
M16	I/O	I/O	I/O
N1	I/O	I/O	I/O
N2	I/O	I/O	I/O
N3	I/O	I/O	I/O
N4	I/O	I/O	I/O
N5	I/O	I/O	I/O
N6	I/O	I/O	I/O
N7	I/O	I/O	I/O
N8	I/O	I/O	I/O
N9	I/O	I/O	I/O
N10	I/O	I/O	I/O
N11	I/O	I/O	I/O
N12	I/O	I/O	I/O
N13	I/O	I/O	I/O
N14	I/O	I/O	I/O
N15	I/O	I/O	I/O
N16	I/O	I/O	I/O
P1	I/O	I/O	I/O
P2	GND	GND	GND
P3	I/O	I/O	I/O
P4	I/O	I/O	I/O
P5	NC	I/O	I/O
P6	I/O	I/O	I/O
P7	I/O	I/O	I/O
P8	I/O	I/O	I/O
P9	I/O	I/O	I/O
P10	NC	I/O	I/O
P11	I/O	I/O	I/O
P12	I/O	I/O	I/O
P13	V _{CCA}	V _{CCA}	V _{CCA}
P14	I/O	I/O	I/O

Previous Version	Changes in Current Version (v5.3)	Page
v4.0 (continued)	Table 2-12 was updated.	2-11
	The was updated.	2-14
	The "Sample Path Calculations" were updated.	2-14
	Table 2-13 was updated.	2-17
	Table 2-13 was updated.	2-17
	All timing tables were updated.	2-18 to 2-52
v3.0	The "Actel Secure Programming Technology with FuseLock™ Prevents Reverse Engineering and Design Theft" section was updated.	1-i
	The "Ordering Information" section was updated.	1-ii
	The "Temperature Grade Offering" section was updated.	1-iii
	The Figure 1-1 • SX-A Family Interconnect Elements was updated.	1-1
	The "Clock Resources" section was updated.	1-5
	The Table 1-1 • SX-A Clock Resources is new.	1-5
	The "User Security" section is new.	1-7
	The "I/O Modules" section was updated.	1-7
	The Table 1-2 • I/O Features was updated.	1-8
	The Table 1-3 • I/O Characteristics for All I/O Configurations is new.	1-8
	The Table 1-4 • Power-Up Time at which I/Os Become Active is new.	1-8
	The Figure 1-12 • Device Selection Wizard is new.	1-9
	The "Boundary-Scan Pin Configurations and Functions" section is new.	1-9
	The Table 1-9 • Device Configuration Options for Probe Capability (TRST Pin Reserved) is new.	1-11
	The "SX-A Probe Circuit Control Pins" section was updated.	1-12
	The "Design Considerations" section was updated.	1-12
	The Figure 1-13 • Probe Setup was updated.	1-12
	The Design Environment was updated.	1-13
	The Figure 1-13 • Design Flow is new.	1-11
	The "Absolute Maximum Ratings*" section was updated.	1-12
	The "Recommended Operating Conditions" section was updated.	1-12
	The "Electrical Specifications" section was updated.	1-12
	The "2.5V LVCMOS2 Electrical Specifications" section was updated.	1-13
	The "SX-A Timing Model" and "Sample Path Calculations" equations were updated.	1-23
	The "Pin Description" section was updated.	1-15
v2.0.1	The "Design Environment" section has been updated.	1-13
	The "I/O Modules" section, and Table 1-2 • I/O Features have been updated.	1-8
	The "SX-A Timing Model" section and the "Timing Characteristics" section have new timing numbers.	1-23